

Reg No.: _____

Name: _____

APJ ABDUL KALAM TECHNOLOGICAL UNIVERSITY

Sixth Semester B.Tech Degree (S,FE) Examination May 2022 (2015 Scheme)

**Course Code: EC304****Course Name: VLSI**

Max. Marks: 100

Duration: 3 Hours

PART A*Answer any two full questions, each carries 15 marks*

Marks

- 1 a) With neat sketches explain Czochralski process of crystal growth. Comment on the quality of the crystals grown through this technique. (8)
- b) Discuss the oxidation technique employed in growing gate oxide and field oxide in MOSFETs. Justify your choice (2)
- c) A dry oxidation process designed to grow 120 nm of oxide on silicon wafers at 900°C. What is the time required to obtain this thickness? What is the time if steam can be used instead? (5)
- ($B/A = 2.63 \times 10^{-6} \mu\text{m}/\text{sec}$, $B = 1.11 \times 10^{-6} \mu\text{m}^2/\text{sec}$ for dry oxidation and $B/A = 4.2 \times 10^{-5} \mu\text{m}/\text{sec}$, $B = 4.32 \times 10^{-6} \mu\text{m}^2/\text{sec}$ for wet oxidation. Assume a fictitious initial thickness of 0.020 μm for dry oxidation.)
- 2 a) Compare two step thermal diffusion and ion implantation techniques with their relative merits and demerits. Draw the doping profiles in each case and explain with necessary modelling equations. (10)
- b) Explain the technique of fabricating resistors and capacitors in integrated circuits. (5)
- 3 a) With sketches, explain the fabrication process flow for realizing a CMOS inverter in N-well technology. Draw the mask for each step assuming positive photo resist. (10)
- b) Define the following terms in the context of photolithography and explain how these terms are related to the pattern which is transferred on to silicon. (5)
- i) Resolution ii) Depth of focus iii) Contrast

PART B*Answer any two full questions, each carries 15 marks*

- 4 a) Draw the DC transfer characteristics of CMOS inverter. Derive an expression for the switching threshold of the device and explain how the β ratios of the devices affects the transfer characteristics, (10)

- b) What are the sources of static power dissipation in CMOS inverter? (2)
- c) Realize the logic function in complementary CMOS logic. (3)
- $$Y = \overline{A + C(B + D)}$$
- 5 a) Draw the schematic, stick diagram and layout of two input NOR gates. (10)
- b) List the factors on which the delay of CMOS inverter depend? Discuss methods to reduce this delay. (5)
- 6 a) Comment on the use of level restorer in pass transistor logic? With a circuit diagram and explain the operation. (5)
- b) Discuss transmission gate logic? State the advantages over pass transistor logic? (3)
- c) Implement 2:1 mux using transmission gates. Implement 4:1 mux using three 2:1 muxs. Explain the operation of the circuit. (7)

PART C

Answer any two full questions, each carries 20 marks

- 7 a) Draw the circuit of 6T SRAM cell. Explain its read and write operations. (10)
Comment on the sizing constraints of the transistors.
- b) Design a 4x4 NAND ROM to store the data (5)
- | | | | | |
|---------|------|------|------|------|
| Address | 0 | 1 | 2 | 3 |
| Data | 1010 | 1100 | 0100 | 1111 |
- c) Design a PLA with outputs, the sum of the following minterms. (5)
 $F_1 = m_1 + m_6$, $F_2 = m_5 + m_6 + m_7$, $F_3 = m_3 + m_2 + m_4 + m_7$
- 8 a) Draw and explain the architecture of CLB based FPGA. (10)
- b) Design a 16-bit linear carry select adder. Mark the critical path and calculate its worst-case delay. (10)
- 9 a) Design a circuit to multiply two 4-bit binary numbers $A_3A_2A_1A_0$ and $B_3B_2B_1B_0$ (10)
- b) Design a 32-bit carry bypass adder using 4-bit carry bypass technique. Mark the critical path and calculate its worst-case delay. (10)
